

FDD8874 / FDU8874 N-Channel PowerTrench[®] MOSFET

30V, 116A, 5.1mΩ

General Description

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low $r_{DS(ON)}$ and fast switching speed.

ApplicationsDC/DC converters

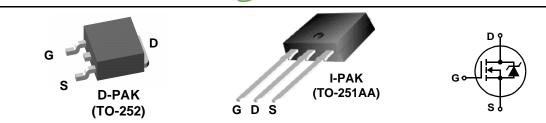


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FDD8874 / FDU8874

Features

- r_{DS(ON)} = 5.1mΩ, V_{GS} = 10V, I_D = 35A
- $r_{DS(ON)} = 6.4m\Omega$, $V_{GS} = 4.5V$, $I_D = 35A$
- High performance trench technology for extremely low $r_{\mbox{DS}(\mbox{ON})}$
- Low gate charge
- High power and current handling capability
- RoHS Compliant



MOSFET Maximum Ratings T_C = 25°C unless otherwise noted

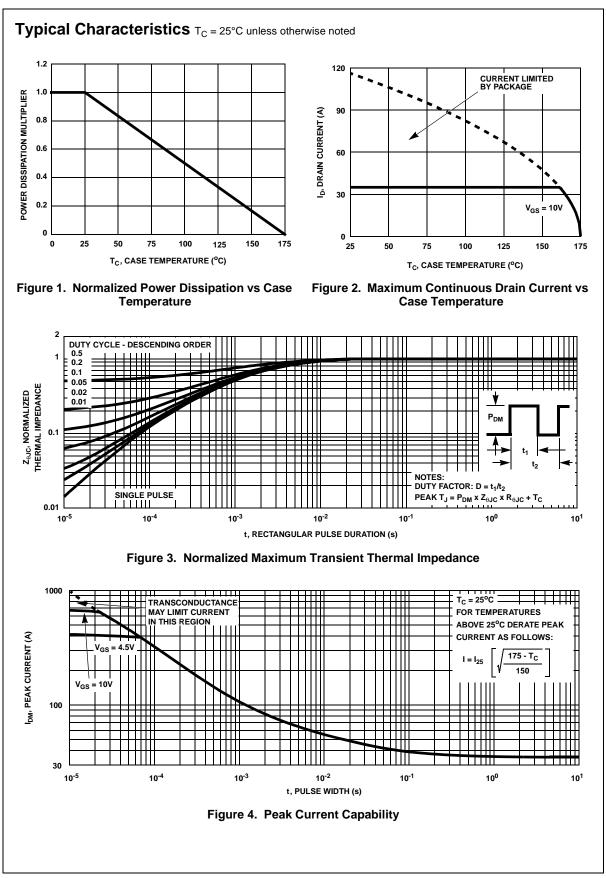
Symbol	Parameter	Ratings	Units	
V _{DSS}	Drain to Source Voltage	30	V	
V _{GS}	Gate to Source Voltage	±20	V	
ID	Drain Current			
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 10V$) (Note 1)	116	А	
	Continuous ($T_C = 25^{\circ}C$, $V_{GS} = 4.5V$) (Note 1)	103	Α	
	Continuous ($T_{amb} = 25^{\circ}C$, $V_{GS} = 10V$, with $R_{\theta JA} = 52^{\circ}C/W$)	18	Α	
	Pulsed	Figure 4	Α	
E _{AS}	Single Pulse Avalanche Energy (Note 2)	240	mJ	
P _D	Power dissipation	110	W	
	Derate above 25°C	0.73	W/ºC	
T _J , T _{STG}	Operating and Storage Temperature	-55 to 175	°C	

Thermal Characteristics

$R_{ extsf{ heta}JC}$	Thermal Resistance Junction to Case TO-252, TO-251	1.36	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient TO-252, TO-251	100	°C/W
R_{\thetaJA}	Thermal Resistance Junction to Ambient TO-252, 1in ² copper pad area	52	°C/W

Device	Marking	Device	Package	Reel Size	Tape	Width	Quar	ntity	
FDD8874		FDD8874	TO-252AA	13"	16mm		2500 units		
FDU8874 FDU8874			TO-251AA	TO-251AA Tube		N/A (Tube)		75 units	
	cal Chara	icteristics T _C = 25					1		
Symbol		Parameter	Test	Conditions	Min	Тур	Max	Units	
Off Char	acteristics								
B _{VDSS}	Drain to So	urce Breakdown Voltag	_	$V_{GS} = 0V$	30	-	-	V	
I _{DSS}	Zero Gate	Voltage Drain Current	$V_{DS} = 24V$		-	-	1	μA	
		-	$V_{GS} = 0V$	$T_{C} = 150^{\circ}C$	-	-	250	•	
I _{GSS}	Gate to Sou	urce Leakage Current	$V_{GS} = \pm 20V$		-	-	±100	nA	
On Char	acteristics								
V _{GS(TH)}	Gate to Sou	urce Threshold Voltage	$V_{GS} = V_{DS},$	I _D = 250μA	1.2	-	2.5	V	
			I _D = 35A, V _C		-	0.0042	0.0051		
[DO(ON)	Drain to So	urce On Resistance	I _D = 35A, V _C	_{SS} = 4.5V	-	0.0052	0.0064	Ω	
r _{DS(ON)}			$I_{\rm D} = 35A, V_{\rm C}$	_{SS} = 10V,	-	0.0069	0.0083		
			$T_{J} = 175^{\circ}C$						
Dynamic	Character	istics							
C _{ISS}	Input Capa	citance			-	2990	-	pF	
C _{OSS}	Output Cap	acitance	V _{DS} = 15V, ` f = 1MHz	v _{GS} = 0v,	-	585	-	pF	
C _{RSS}	Reverse Tra	ansfer Capacitance			-	340	-	pF	
R _G	Gate Resis	tance	$V_{GS} = 0.5 V,$		-	2.0	-	Ω	
Q _{g(TOT)}		Charge at 10V	$V_{GS} = 0V$ to		-	54	72	nC	
Q _{g(5)}		Charge at 5V	V _{GS} = 0V to	5V	-	29	38	nC	
Q _{g(TH)}		Gate Charge	$V_{GS} = 0V$ to	$\frac{1}{1V} V_{DD} = 15V$ $I_{D} = 35A$	-	3.0	4.0	nC	
Q _{gs}		urce Gate Charge		$I_q = 1.0 \text{mA}$	-	8.0	-	nC	
Q _{gs2}	9	ge Threshold to Plateau	1	Ū.	-	5.0	-	nC	
Q _{gd}	Gate to Dra	ain "Miller" Charge			-	10	-	nC	
Switchin	g Characte	eristics (V _{GS} = 10V)							
t _{ON}	Turn-On Tir	ne			-	-	156	ns	
t _{d(ON)}	Turn-On De	ay Time		$V_{DD} = 15V, I_D = 35A$ $V_{GS} = 10V, R_{GS} = 4.7\Omega$		9	-	ns	
t _r	Rise Time					96	-	ns	
t _{d(OFF)}	Turn-Off De	ay Time	V _{GS} = 10V,			47	-	ns	
t _f	Fall Time					37	-	ns	
t _{OFF}	Turn-Off Tir	ne				-	126	ns	
Drain-So	ource Diode	e Characteristics							
	Source to Drain Diode Voltage		I _{SD} = 35A		-	-	1.25	V	
V _{SD}			I _{SD} = 15A		-	-	1.0	V	
t _{rr}	Reverse Re	Reverse Recovery Time		I _{SD} /dt = 100A/μs	-	-	32	ns	
	Reverse Recovered Charge			I _{SD} /dt = 100A/µs	-	-	18	nC	

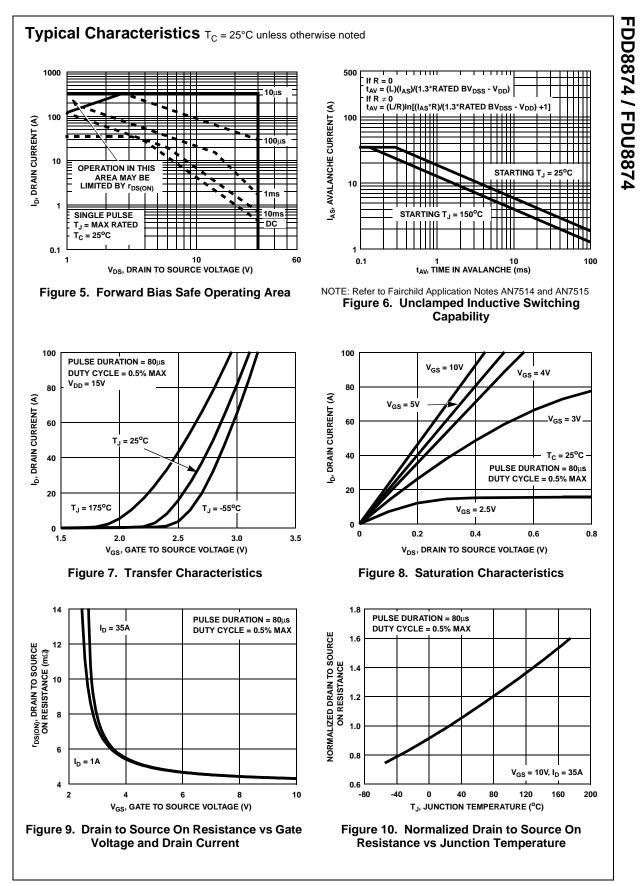
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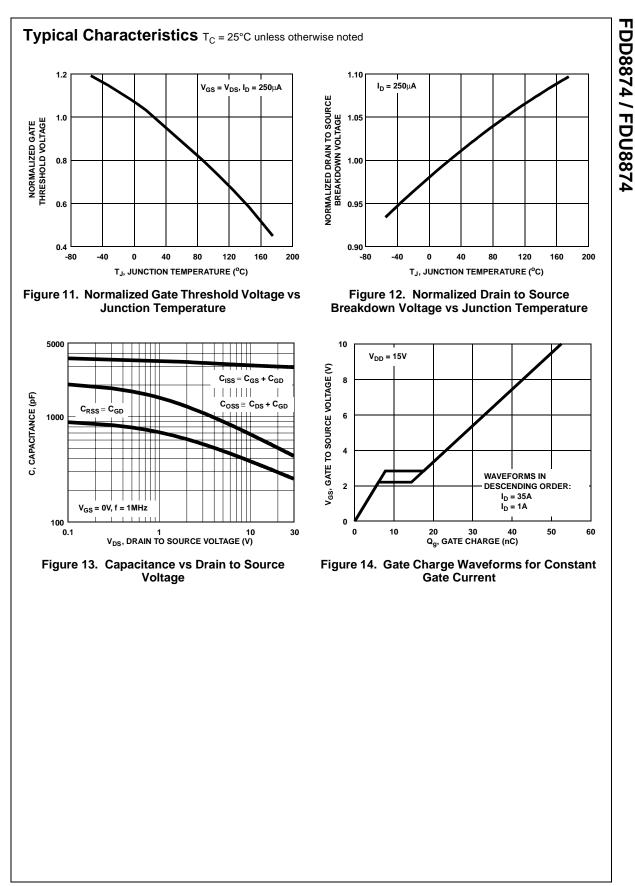
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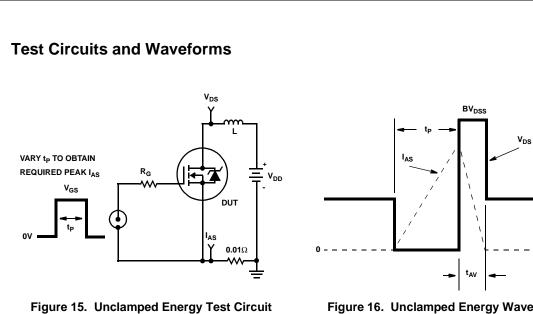
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 V_{DD}

Figure 16. Unclamped Energy Waveforms

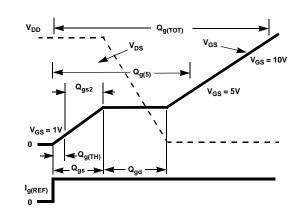
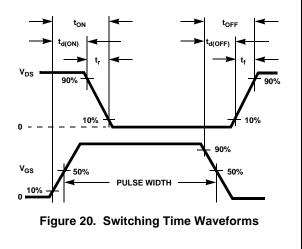


Figure 18. Gate Charge Waveforms



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V_{GS} V_{DD} DUT Ig(REF)

Figure 17. Gate Charge Test Circuit

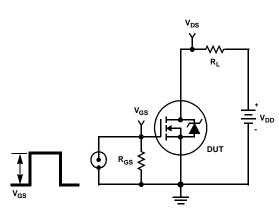


Figure 19. Switching Time Test Circuit

Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature, T_{JM} , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation, P_{DM} , in an application. Therefore the application's ambient temperature, T_A (°C), and thermal resistance $R_{\theta JA}$ (°C/W) must be reviewed to ensure that T_{JM} is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}}$$
(EQ. 1)

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of P_{DM} is complex and influenced by many factors:

- 1. Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- 6. For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the $R_{\theta,JA}$ for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

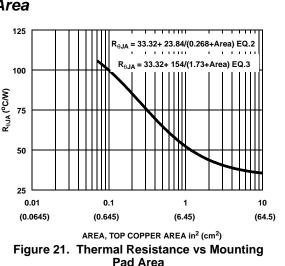
Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

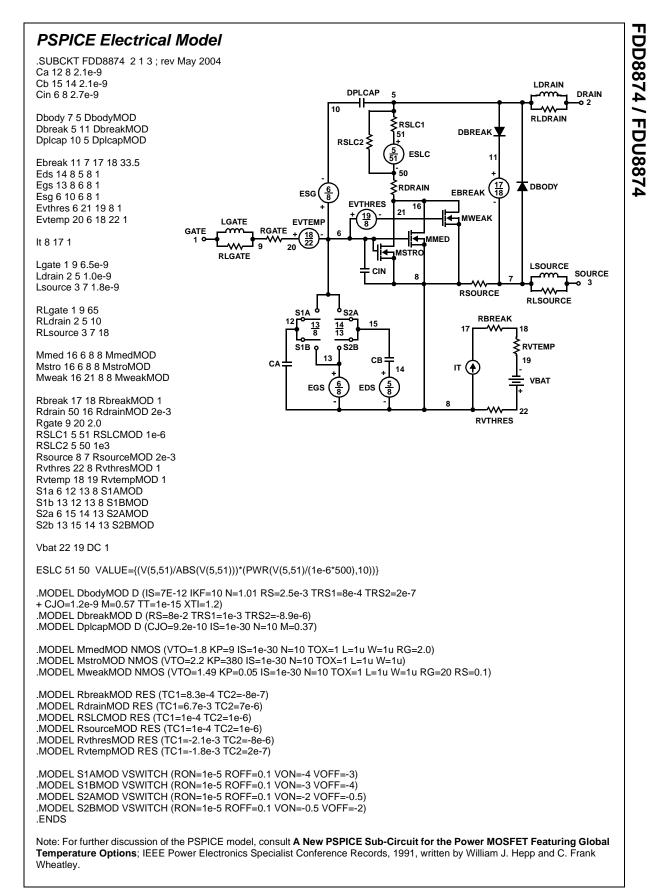
$$R_{\Theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

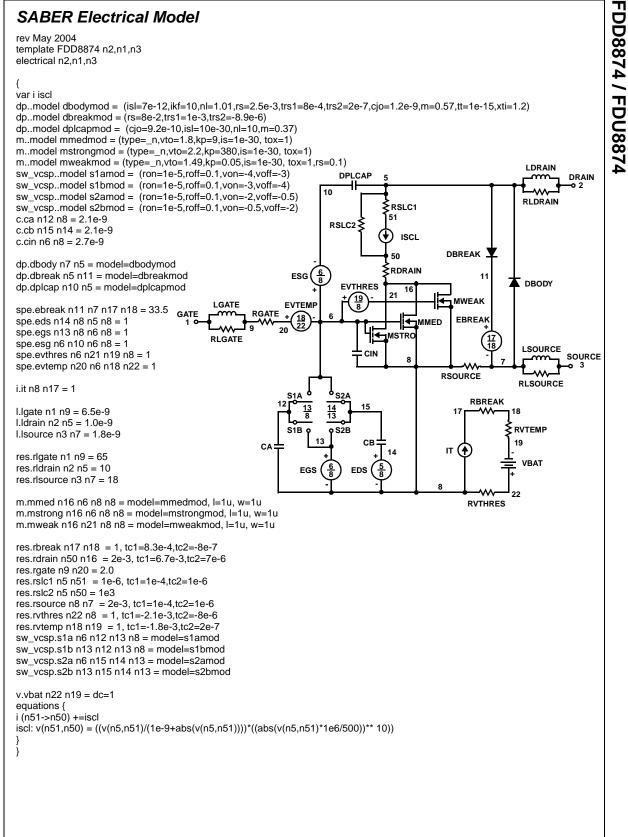


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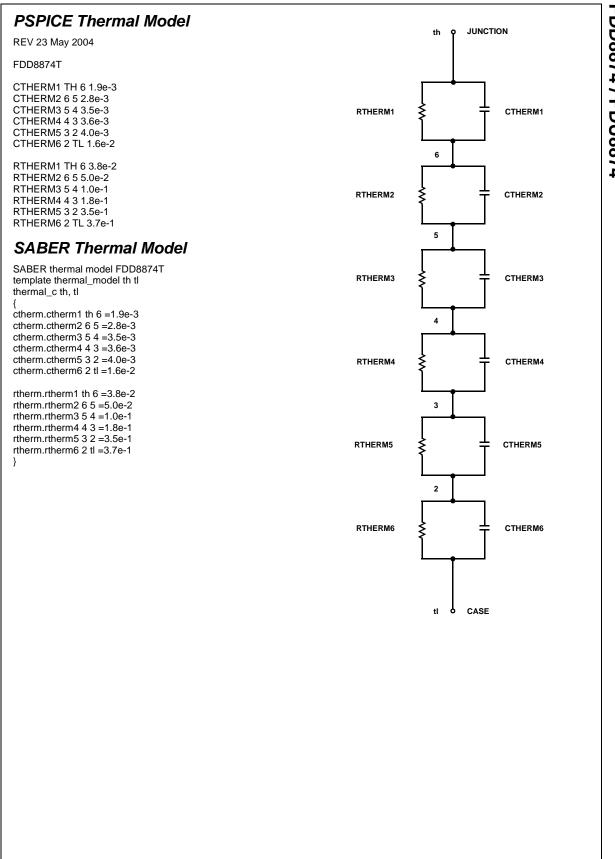
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SABER Electrical Model

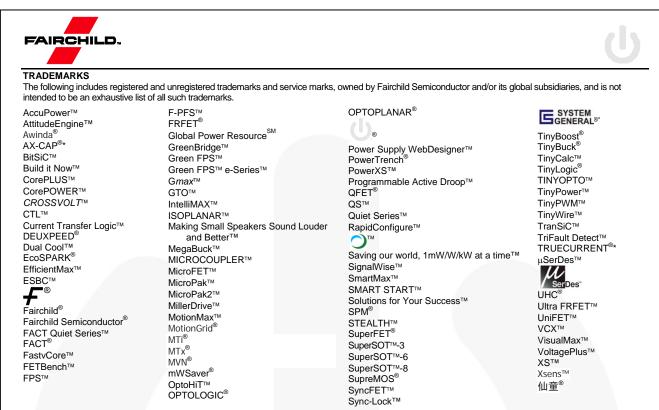


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